DECEMBER 1983-REVISED MARCH 1988

- Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages
- Dependable Texas Instruments Quality and Reliability

description

These devices contain dual 4-input positive NOR gates with strobe. They perform the Boolean function:

$$Y = \overline{G(A+B+C+D)}$$
(with 1X and 1 \overline{X} of '23 left open).

The SN5423 and the SN5425 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$. The SN7423 and the SN7425 are characterized for operation from 0 $^{\circ}\text{C}$ to 70 $^{\circ}\text{C}$.

FUNCTION TABLE

	11	NPU1		OUTPUT	
A	В	С	D	G	Y
Н	×	×	×	н	L
x	Н	×	Х	н	L
x	×	Н	×	Н	L
x	×	х	Н	Н	L
L	L	L	L	X	н
×	×	х	Х	L	H

Expander inputs are open,
H = high level, L = low level, X = irrelevant

SN5423 . . . J OR W PACKAGE SN7423 . . . N PACKAGE (TOP VIEW)

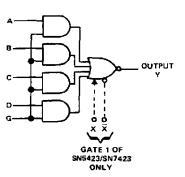
1X [ſī	U ₁₆	<u>ا</u> [<u>√_</u> CC
1A [12	15	□ .	ıχ
1B [3	14]2	2D
1G 🛚	4	13		2C
1C [5	12];	2G
1D [6	11]2	2B
1Y [7	10]2	2A
GND [8	9	<u> </u>	2Y

SN5425 . . . J OR W PACKAGE SN7425 . . . N PACKAGE

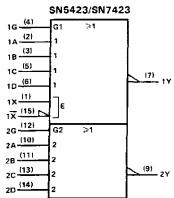
(TOP VIEW)

1A □	vc	С
1В [2	13 2D	
1G □3	12 12C	
10 🗖 ₄	11] 2G	
10 🗖 5	10 2B	
1Ү 🗖 6	9 <u> </u>	
GND 7	8 2Y	

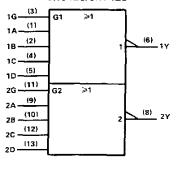
logic diagram



logic symbols†



SN5425/SN7425



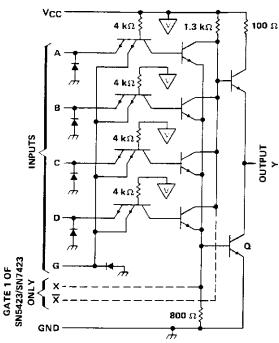
[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers are for J, N, or W packages.

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SN5423, SN5425, SN7423, SNSN7425 DUAL 4-INPUT NOR GATES WITH STROBE

schematic (each gate)



NOTES: A. Component values shown are nominal.

- B. Both expander inputs are used simultaneously for expanding.
- C. If expander is not used leave X and X open.
- D. A total of four expander gates can be connected to the expander inputs.

VCC bus

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage VCC (see Note 1)	
Input voltage (see Note 1)	5.5 V
Interemitter voltage (see Note 2)	
Operating free-air temperature range: SN5423, SN5425 Circuits	55°C to 125°C
SN7423, SN7425 Circuits	0°C to 70°C
Storage temperature range	$ 65^{\circ}C$ to $150^{\circ}C$

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.

2. This is the voltage between two emitters of a multiple-emitter transistor.

recommended operating conditions

			'23 , '25				
			MIN NOM 4.5 5	MAX	UNIT		
		54 Family	4.5	5	5.5	v	
vcc		74 Family	4.75	5	5.25		
VIH	High-level input voltage		2	•		٧	
VIL	Low-level input voltage				0.8	٧	
Гон	High-level output current		1		- 0.8	mA	
		54 Family	ily		16	-^	
OF	Low-level output current	74 Family			16	mA	
		54 Family	- 55		125	°c	
T_A	Operating free-air temperature range	74 Family	0		70	C	

The '23 is designed for use with up to four '60 expanders.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAF	RAMETER		TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
V _I		V _{CC} = MIN,	l _t = — 12 mA					– 1.5	V
Voн		VCC = MIN,	V _{IL} = 0.8 V,	Nm 8.0 - = HOI		2.4	3.4		V
VOL		V _{CC} = MIN,	V _{IH} = 2 V,	IOL = 16 mA			0.2	0.4	· V
11		V _{CC} = MAX,	V ₁ = 5.5 V					1	mA
	data inputs	V _{CC} = MAX,	V ₁ = 2.4 V					40	ДД
¹IH	strobe inputs	4CC - 141AA,	V - 2.4 V					160	#7
	data inputs	V _{CC} = MAX,	V. = 0.4 V					1.6	mA
IJL	strobe inputs	VCC - MAA,	V1 - 0.4 V					- 6.4	
		\/ MAY			54 Family	- 20		- 55	•
loss		V _{CC} = MAX			74 Family	– 18		– 55	mA
Іссн		V _{CC} = MAX,	All inputs at 0	7			8	16	mΑ
ICCL		V _{CC} = MAX,	All inputs at 5	V			10	19	mΑ

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander inputs X and X are open.

electrical characteristics (SN5423 circuits) using expander inputs, V_{CC} = 4.5 V, T_A = - 55°C

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
١x̄	Expander current	V _X x = 0.4 V,	I _{OL} = 16 mA				- 3.5	mΑ
VBE(Q)	Base-Emitter voltage of output transistor (Q)	I _{OL} = 16 mA,	$I_X + I_X^{-} = 0.41 \text{ mA},$	$R_{XX} = 0$			1.1	٧
Voн	High-level output voltage	$1_{OH} = -0.4 \text{ mA},$	I _X = 0.15 mA,	I = − 0.15 mA	2.4	3.4		٧
VOL	Low-level output voltage	I _{OL} = 16 mA,	$I_X + I_{\overline{X}} = 0.3 \text{ mA},$	R _X = 114 Ω		0.2	0.4	V

electrical characteristics (SN7423 circuits) using expander inputs, V_{CC} = 4.75 V, T_A = 0°C

	PARAMETER	TEST	CONDITIONS	. <u></u>	MIN	TYP	MAX	UNIT
ıχ	Expander current	V _X \overline{\overline{X}} = 0.4 \overline{V},	I _{OL} = 16 mA				- 3.8	mΑ
VBE(Q)	Base-Emitter voltage of output transistor (Q)	I _{OL} = 16 mA,	I _X + I _X = 0.62 mA,	$R_{X\overline{X}} = 0$			1	٧
Voн	High-level output voltage	I _{OH} = - 0.4 mA,	I _X = 0.27 mA,	1 √ = → 0.27 mA	2.4	3.4		V
VOL	Low-level output voltage	IOL= 16 mA,	$1_{X} + 1_{X} = 0.43 \text{ mA},$	$H_{XX} = 130 \Omega$		0.2	0.4	· v

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$, N = 10, (see note 3)

PARAMETER	TEST CON	IDITIONS	MIN	TYP	MAX	UNIT
tPLH .	RL = 400 Ω,	C _L = 15 pF		13	22	nş
tPHL .	R _L = 400 Ω,	C _L = 15 pF		8	15	ns

NOTE 3: Switching characteristics of the \$N5423 and \$N7424 are tested with the expander pins open.

[‡] All typical values are at V_{CC} = 5 V, T_A = 25° C.

[§] Not more than one output should be shorted at a time.

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